



# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

**GD4 Test Services, Inc.**  
**5301 Riata Park Court, Building E Ste 120A**  
**Austin, TX 78727**  
**(and the satellite locations as listed on the scope)**

Fulfills the requirements of

**ISO/IEC 17025:2017**

and the

**AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program**

In the field of

**TESTING**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

Jason Stine, Vice President

Expiry Date: 29 July 2024

Certificate Number: AT-2892



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory  
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017  
and AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program**

**GD4 Test Services, Inc.**  
5301 Riata Park Court, Building E Ste 120A  
Austin, TX 78727  
George Jastroch [gj@gd4test.com](mailto:gj@gd4test.com)  
512 535 1677

**TESTING**

Valid to: **July 29, 2024**

Certificate Number: **AT-2892**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **GD4 Test Services, Inc.** to perform the following AS6171 slash sheet tests:

**Mechanical**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7	Electronic Components	Hotplate, Multiple Acids
Heated Chemical Test	AS6081, Sect. 4.2.6.4.3, AS6171/2, Sect. 5.3.4 Method D		Multiple Chemicals
X-Ray Inspection	AS6081, Sect. 4.2.6.4.4, AS6171/5		Focal Spot X-Ray
XRF Inspection	AS6081, Sect. 4.2.6.4.5, AS6171/3		Quickshot XRF
Temperature Cycle	MIL-STD-883, Method 1010, AS6081 Sect. C.2 AS6171/7		Blue M Temperature Cycle Chamber
C-SAM	AS6081, Sect. C.6		OKOS Sonoscan
Visual Inspection	AS6081, Sect. 4.2.6.4.2, AS6171/2, Method A and B, AS6171/2, Method E		Multiple Scopes Scale
SEM Surface Texture Analysis	AS6171/2 Method F		Vega Tescan

## Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Solderability	J-STD-002 MIL-STD-883	Electronic Components	Solder Pot AM Scope Stream Ager
Resistance to Solvents	AS6081, Sect. 4.2.6.4.3-A, AS6171/2, Method C		Multiple Chemicals

## Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test: Resistors, Capacitors, Inductors, Relays, connectors, Microcircuits and Semiconductor devices	AS6171/7 Table 2, AS6081, Sect. C.3	Electronic Components	Multiple A.T.E. Equipment Sets

## SATELLITE SITE

### GD4 Test Services, Inc.

12505 Starkey Road, Suite N  
Largo, FL 33773  
George Jastroch [gj@gd4test.com](mailto:gj@gd4test.com)  
512 535 1677

## TESTING

### Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7	Electronic Components	Hotplate, Multiple Acids
Heated Chemical Test	AS6081, Sect. 4.2.6.4.3, AS6171/2, Sect. 5.3.4 Method D		Multiple Chemicals
X-Ray Inspection	AS6081, Sect. 4.2.6.4.4, AS6171/5		Focal Spot X-Ray
XRF Inspection	AS6081, Sect. 4.2.6.4.5, AS6171/3		Quickshot XRF
Visual Inspection	AS6081, Sect. 4.2.6.4.2, AS6171/2, Method A and B, AS6171/2, Method E		Multiple Scopes Scale
Solderability	J-STD-002 MIL-STD-883		Solder Pot AM Scope Stream Ager
Resistance to Solvents	AS6081, Sect. 4.2.6.4.3-A, AS6171/2, Method C		Multiple Chemicals

### Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 AS6081 – C.3	Electronic Components	Multiple A.T.E. Equipment Sets

## SATELLITE SITE

### GD4 Test Services, Inc.

95 Horseblock Road, Suite 3  
Yaphank, NY 11980  
George Jastroch [gj@gd4test.com](mailto:gj@gd4test.com)  
512 535 1677

## TESTING

### Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7	Electronic Components	Hotplate, Multiple Acids
Heated Chemical Test	AS6081, Sect. 4.2.6.4.3, AS6171/2, Sect. 5.3.4 Method D		Multiple Chemicals
X-Ray Inspection	AS6081, Sect. 4.2.6.4.4, AS6171/5		Focal Spot X-Ray
XRF Inspection	AS6081, Sect. 4.2.6.4.5, AS6171/3		Quickshot XRF
Visual Inspection	AS6081, Sect. 4.2.6.4.2, AS6171/2, Method A and B, AS6171/2A, Method E		Multiple Scopes Scale
Solderability	J-STD-002 MIL-STD-883		Solder Pot AM Scope Stream Ager
Resistance to Solvents	AS6081, Sect. 4.2.6.4.3-A, AS6171/2, Method C		Multiple Chemicals

## Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test: Resistors, Capacitors, Inductors, Relays, connectors, Microcircuits and Semiconductor devices	AS6171/7 Table 2, AS6081, Sect. C.3	Electronic Components	Multiple A.T.E. Equipment Sets

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-2892.



Jason Stine, Vice President